Applicant(s)/Patent Under Application/Control No. Reexamination 10/708,224 NATSUHARA ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 3742 Sang Y. Paik **U.S. PATENT DOCUMENTS** Date Document Number Name Classification Country Code-Number-Kind Code MM-YYYY 264/605 06-2000 Kobayashi, Hiromichi US-6,071,465 US-В US-С D US-E US-US-F US-G US-Н USı J US-US-Κ

FOREIGN PATENT DOCUMENTS

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